Sheet 1 of 1 APPLICATION NO. ATTY DOCKET NO. Form PTO-1449 US Dept. of Commerce PATENT & TRADEMARK OFFICE D/A0A93 09/761,492 ORMATION DISCLOSURE STATEMENT Christopher J. Spence **APPLICANT** (Use several sheets if necessary) FILING DATE 1/16/2001 **GROUP ART UNIT 2622 U.S. PATENT DOCUMENTS PUBLICATION** SUB INITIAL DATE NAME OF PATENTEE **CLASS CLASS** DOCUMENT NUMBER 358 406 285 11/18/1986 Asano et al. 4,623,938 250 4,314,159 2/2/1982 **Davis** RECEIVED JUN 0 2 2003 **Technology** Center 26**0**0 FOREIGN PATENT DOCUMENTS **TRANSLATION PUBLICATION** NAME OF PATENTEE OR APPLICANT COUNTRY DOCUMENT NUMBER DATE Y/N Υ EP 0 679 010 A2 **Fujitsu Limited** 10/25/1995 **EPC** CLOTHER DOCUMENTS (Including Author (in CAPS), Title, Publication Date, Pages, etc.)

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ATTY DOCKET NO. D/A0A93

APPLICATION NO. 09/761.492

Christopher J. Spencer **APPLICANT** 

**GROUP ART UNIT** 

U.S. PATENT DOCUMENTS

FILING DATE

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EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE	CLASS	SUB CLASS
c.L	4,538,905	9/3/1985	Griego et al.	345 355	139 - <del>14 SH</del>
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**EXAMINER** 

e.L.	KRAIG A. QUINN, "Assembly Of Imaging Arrays For Large Format Documents", Attorney Docket No. D/A0711, U.S. Serial No. 09/677,742

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